

**Lou Molinari**

ESA Corporation/Probe Solutions

***The Thermal Frontier ....***  
**High Temp Probing System Solutions  
and Analysis**

**June 6 to 9, 2010**  
**San Diego, CA USA**



SW Test 2010 – Thermal Probing

# *The Thermal Frontier*

## **-Goals-**

- Agree on the needs/concerns
- Understanding the Environment
- Introducing an Environmental solution
- Justify the *Final Solution*

# ESA Corp & Probe Solutions

- **ESA Corporation:**
  - Provides **E**ngineering **S**cience **A**nalysis solutions, with expertise in Research, Product Development and Business Management
    - Instituted Research and Make Product (RAMP™) methodology for product development/deployment
- **Probe Solutions, *division of ESA Corporation:***
  - Specializes in system enhancements for the semiconductor test industry.

# Needs/Concerns

- Thermal probing is needed as a cost measure for final product throughput and reliability ... so it is here to stay
- Probing solutions vary across many technologies. (Blade, Epoxy, Vertical, Single, Multi-Dut, etc)
- Probe solutions need to support a variety of tester platforms and configurations

So to create a solution that will support this variety of requirements;

**VERY CUSTOM = COSTLY (\$\$\$) for customer**

# Cost Model for User

- Thermal Probing Cost Model (TPCM)

$$\text{TPCM} = \text{PC Manuf Cost} + \text{Operating Cost}$$

# Cost Model for User

- Probe Card Design and Manufacturing Cost
  - Solutions have been developed to minimize effects
    - Resulting in Custom solutions and Fixed cost
- Operating Cost (*Loss of Revenue*)
  - Dwell Time between wafers / lots
    - Variable depending on probe configuration and users modeling and acceptance range
    - “Typical” Dwell Times range from 3 minutes between wafers to 30 minute between lot changes

**NOT BEING ADDRESSED**

# Cost Model for User

- Result of TPCM:
  - Manufacturing Cost of present day solutions, to user, have little opportunity for reduction or change
  - Operating Cost today are dependent on the evaluations performed and the users willingness to take risk to decrease down time
  - **Down Time = Results in loss of revenue and throughput (\$\$\$\$)**

Yet many solutions to date have only solved the individual component to a systematic problem

We have ignored the ***ENVIRONMENT !***



# Case Study

- Design an airplane to go fast .....
- What are in the input conditions ?
- What are the expectations ?
- If we do not properly understand all the environmental conditions .. We get .....





- Will the plane fly?
- Will it go faster?
- Does it meet the environmental conditions?
  - As currently Understood/Defined
- Maybe YES, but is it the best solution, or are the additions just “band-aids/overdesigning” to the real problem, the environment



- Yet if we understood all the requirements , or better controlled /understand the environment while clearly defining the expectations then the original solution could have been adequate

# Probing Application

- Apply similar thinking in understanding the Probing Environment
- Stop developing solutions that are not addressing the real issue ... the environment

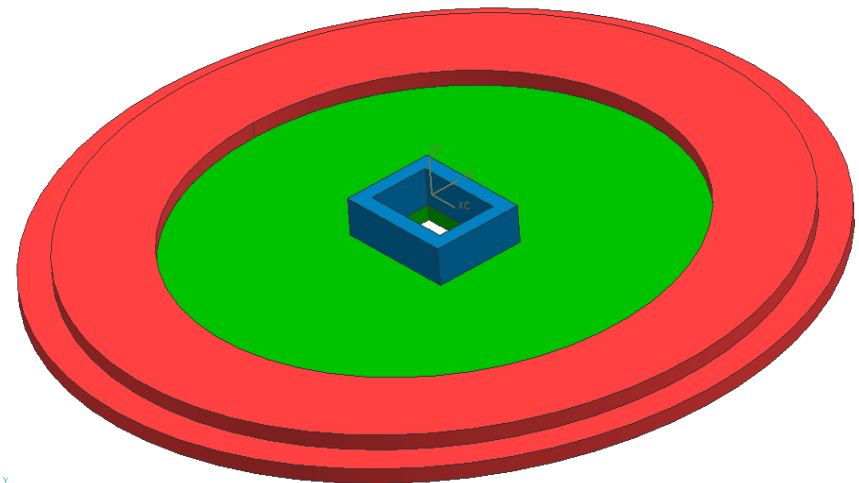
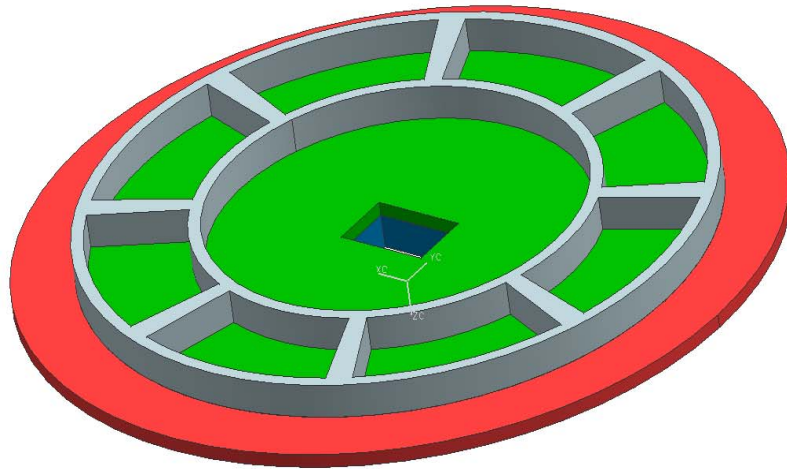
# Environmental Probe Card Control Unit (PCECU)

- *A solution that addresses the environmental conditions, while addressing cost and operational factors of the end user*

# Modeling Analysis

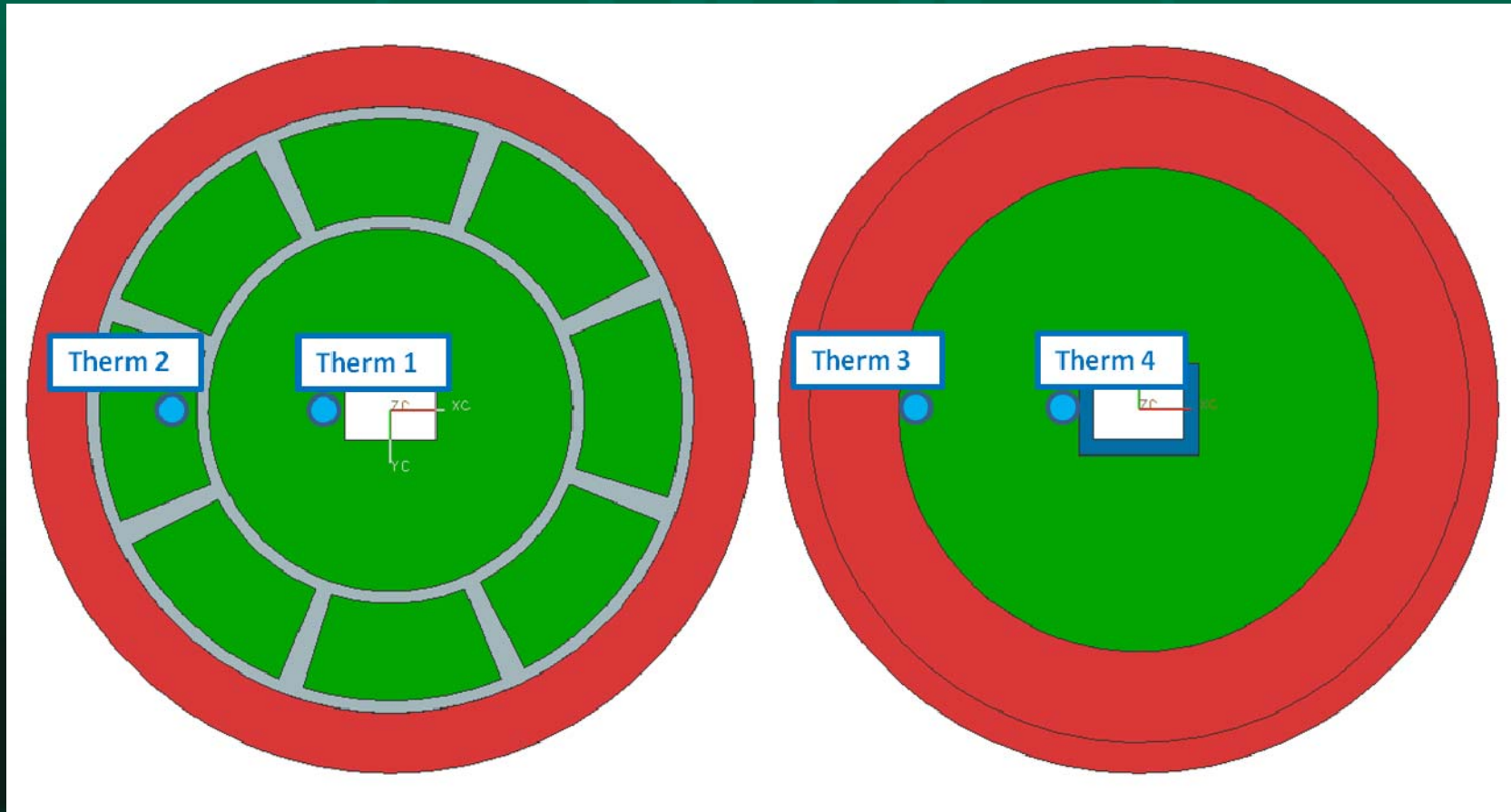
- The focus of this analysis is to understand and demonstrate the impacts due to the environment
- This presentation will not cover the secondary mechanical solutions developed to date
  - But what drove them to be developed

# Modeling Analysis





# Modeling Analysis



# Modeling Analysis

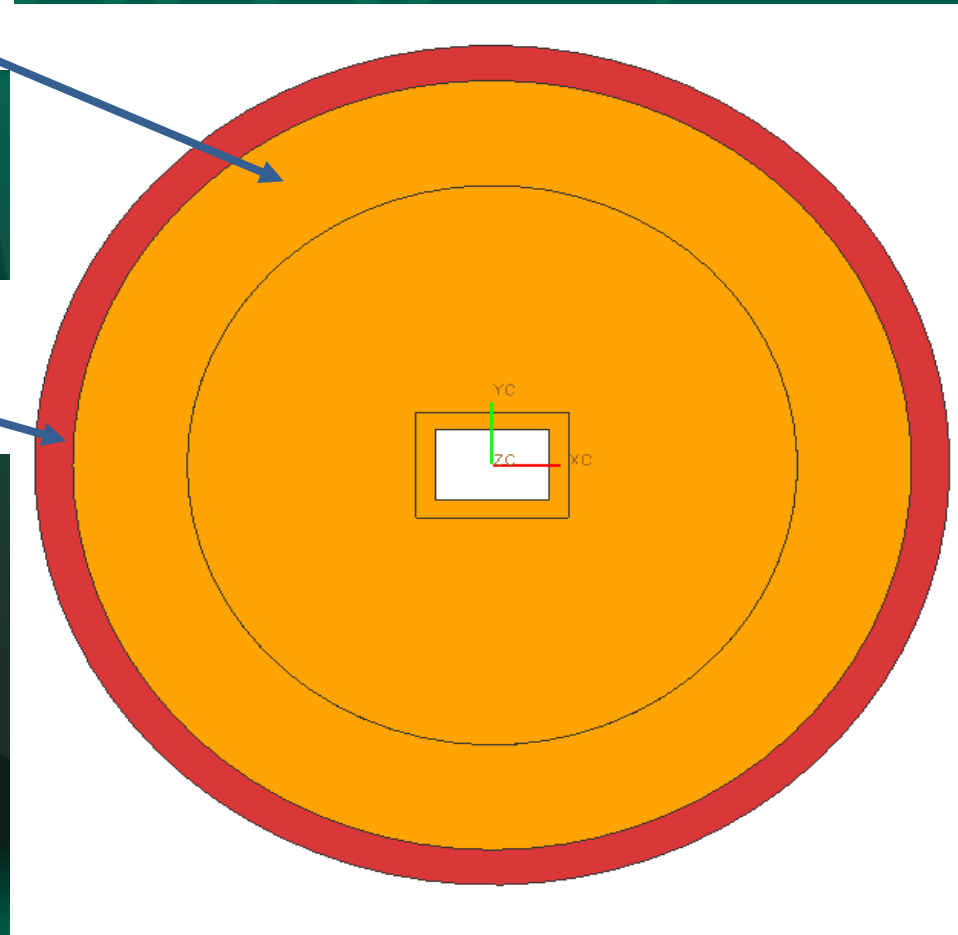
## *Determine PCECU Effectiveness*

- Environment Conditions:
  - Hot Chuck and PCECU heater activated simultaneously
    - Probe card temperature to monitored (stability =  $\Delta > 0.5$  deg. C)
    - 120 deg. C = Hot chuck temp
    - Tray lip is insulated
    - PCECU Heater thermostat is set to 105 deg. C
  - Consistent with normal ATE process (wafer re-load process)
    - Hot chuck is removed from proximity for a period of 60 sec
    - Probe card temperature is monitored at 4 locations
    - Temperature readings are taken at 30 & 60 sec intervals
  - Hot chuck is moved back to probing position
    - Probe card temperature to monitored (stability =  $\Delta > 0.5$  deg. C)

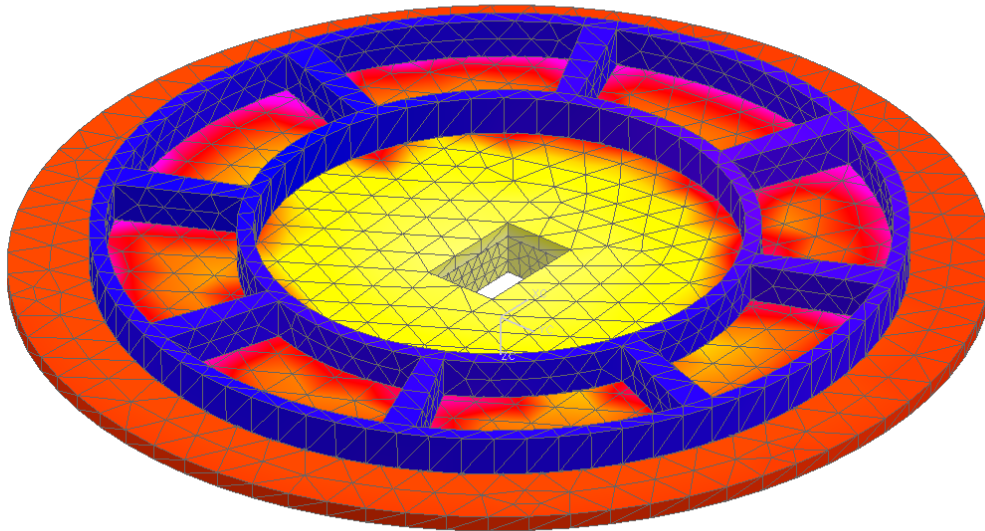
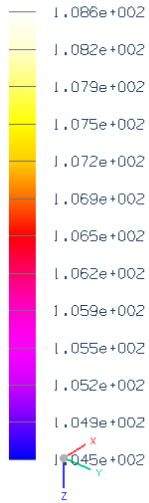
# Model Properties

Convection and radiation boundary conditions applied to orange faces.

Tray Lip (red) is kept perfectly insulated.

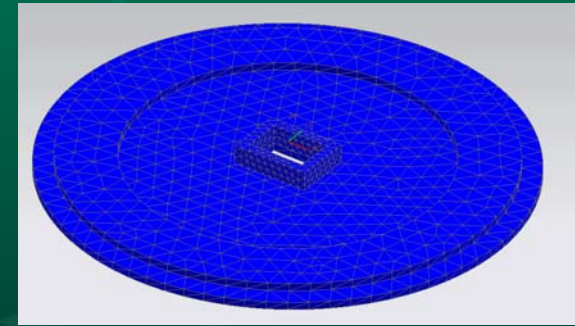


probe\_card\_assem\_thermal\_sim\_RB : LC1-heater-insulated\_lip Result  
Load Case 1, Increment 18, Time = 4.250e+002 s  
Temperature - Nodal, Scalar  
Min : 1.045e+002, Max : 1.086e+002, C

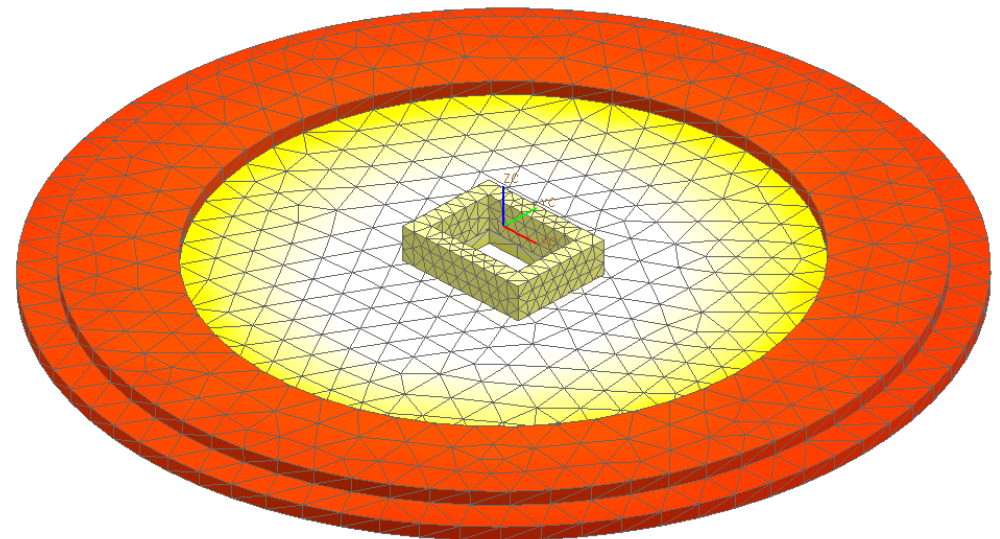
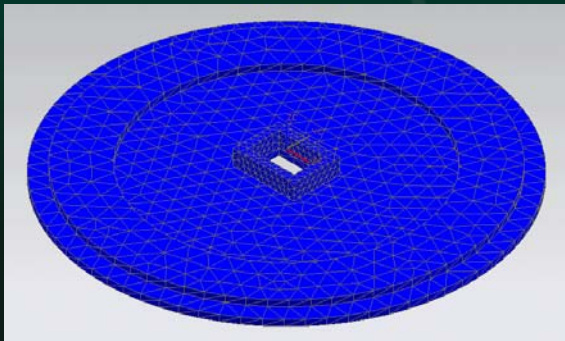
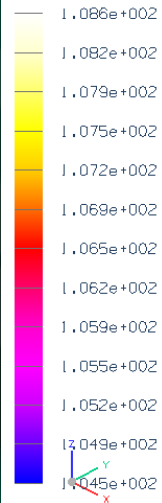


# Fringe Plots

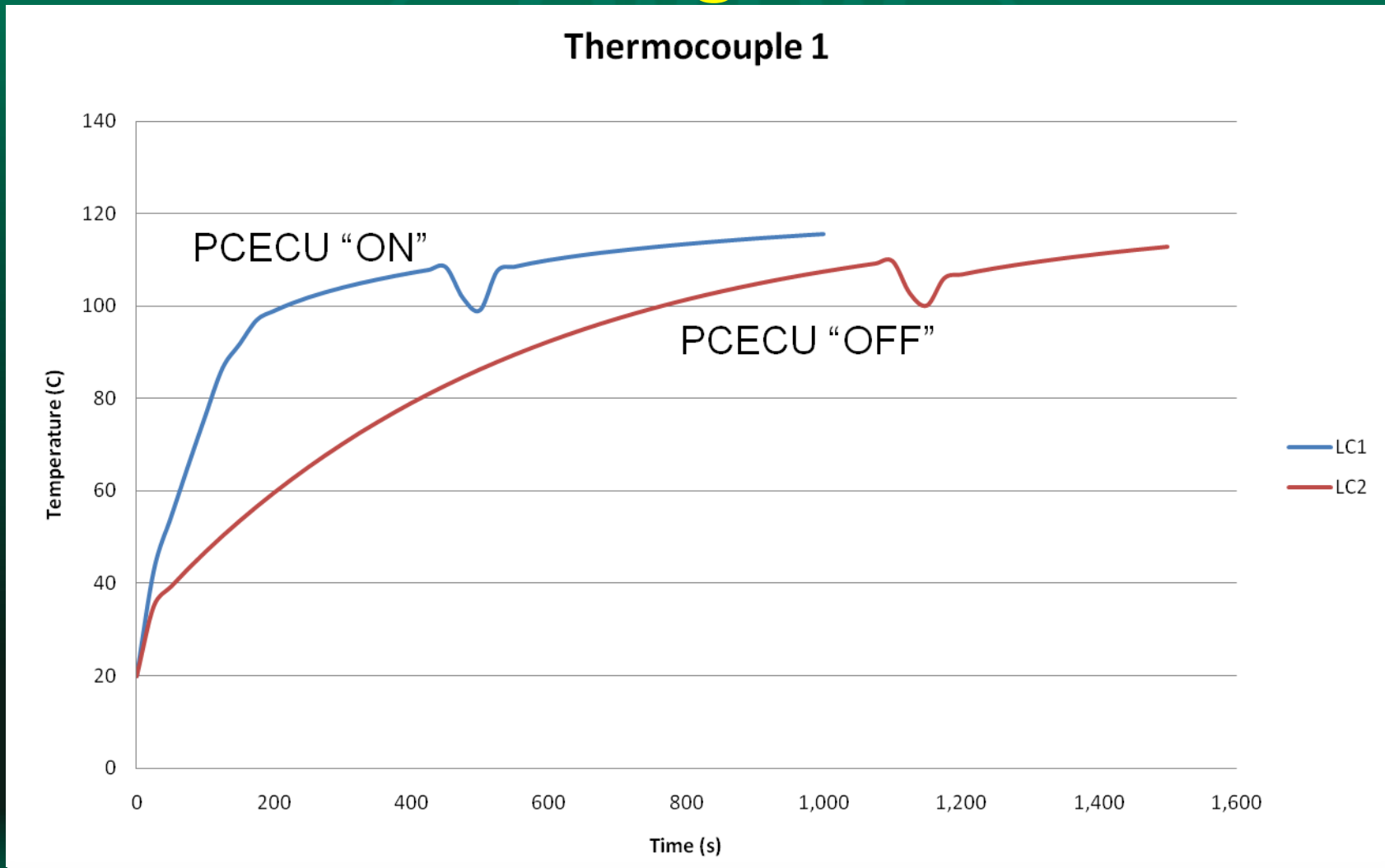
## Model



probe\_card\_assem\_thermal\_sim\_RB : LC1-heater-insulated\_lip Result  
Load Case 1, Increment 18, Time = 4.250e+002 s  
Temperature - Nodal, Scalar  
Min : 1.045e+002, Max : 1.086e+002, C



# Modeling Results



# Modeling Conclusions

- Probe Card stabilizes at 109 deg C, both modes
- PCECU reaches stability with 60% improvement
- No significant delta seen with a 60 sec reload
- Model demonstrates effectiveness of PCECU

# Environment Implementation

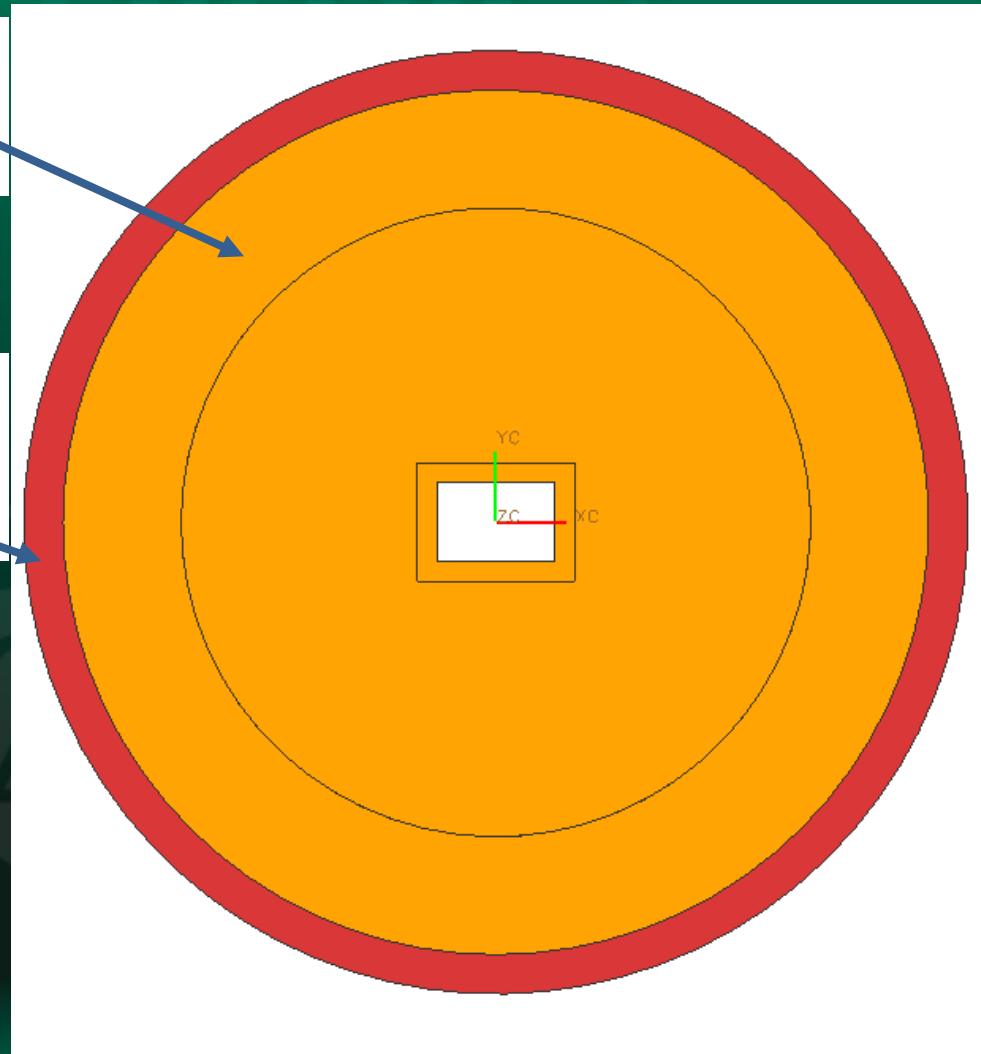
- Environment Conditions:
  - Hot Chuck and PCECU heater activated simultaneously
    - Probe card temperature to monitored (stability =  $\Delta > 0.5$  deg. C)
    - 120 deg. C = Hot chuck temp
    - **Support lip not insulated and conducts to a temperature of 20 deg. C**
    - **PCECU Heater thermostat is set to 90 deg. C**
  - Consistent with normal ATE process (wafer re-load process)
    - Hot chuck is removed from proximity for a period of 60 sec
    - Probe card temperature is monitored at 4 locations
    - Temperature readings are taken at 30 & 60 sec intervals
  - Hot chuck is moved back to probing position
    - Probe card temperature to monitored (stability =  $\Delta > 0.5$  deg. C)



# Environment Properties

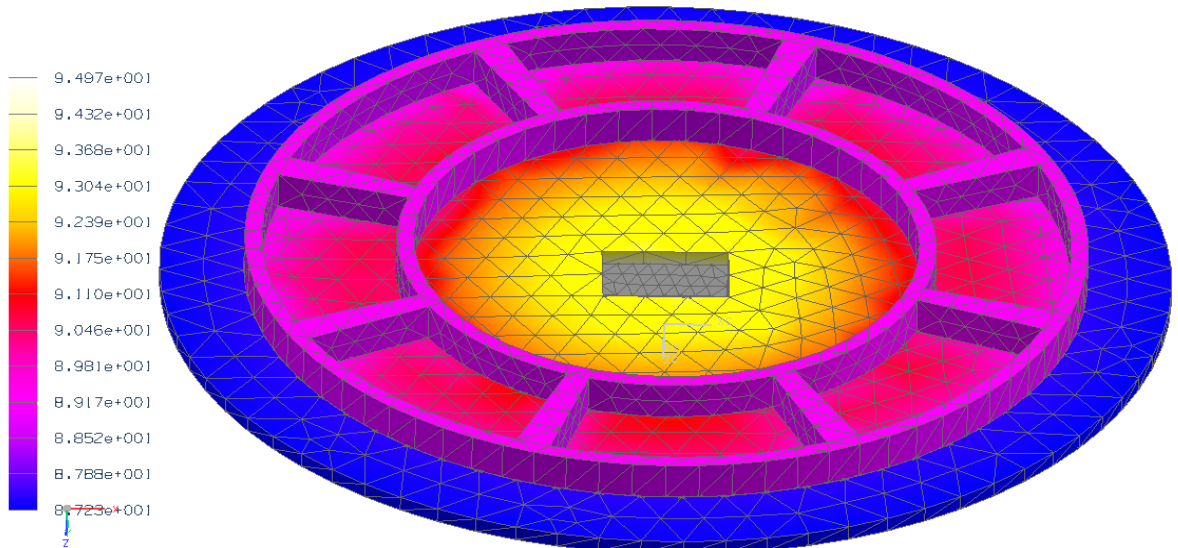
Convection and radiation boundary conditions applied to orange faces.

Tray Lip (red) not insulated and conducts to an ambient temperature of 20 °C





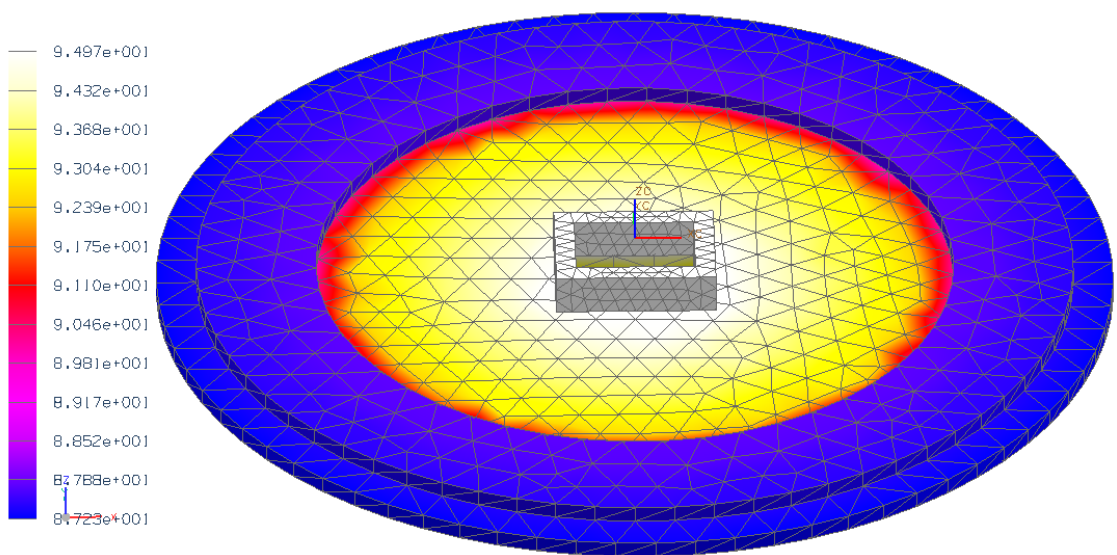
probe\_card\_assem\_thermal\_sim\_RA : LC3b-heater-convecting-1ip Result  
Load Case 1, Increment 18, Time : 4.250e+002 s  
Temperature - Nodal, Scalar  
Min : 8.723e+001, Max : 9.497e+001, C



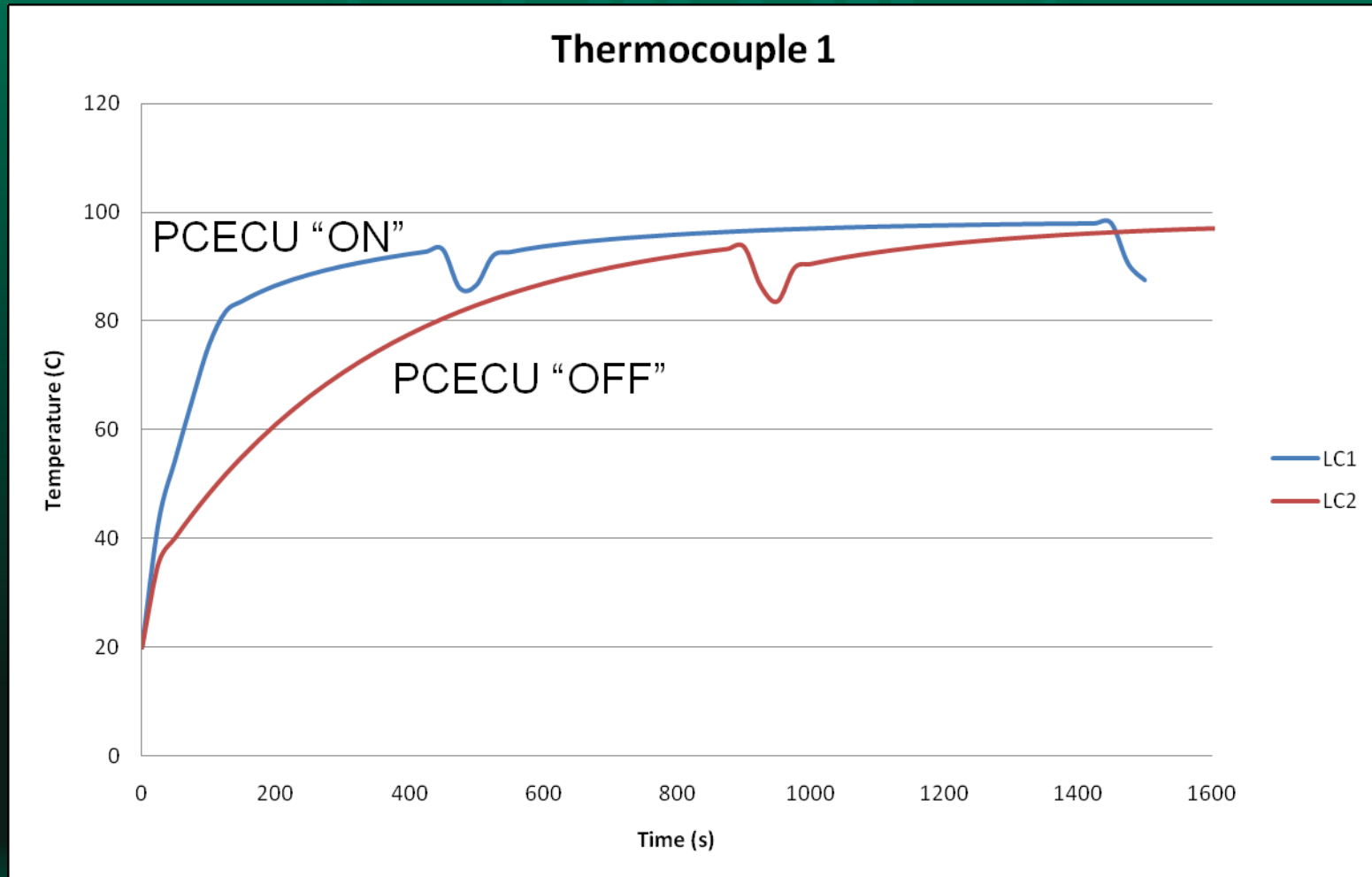
# Fringe Plots

## Environment

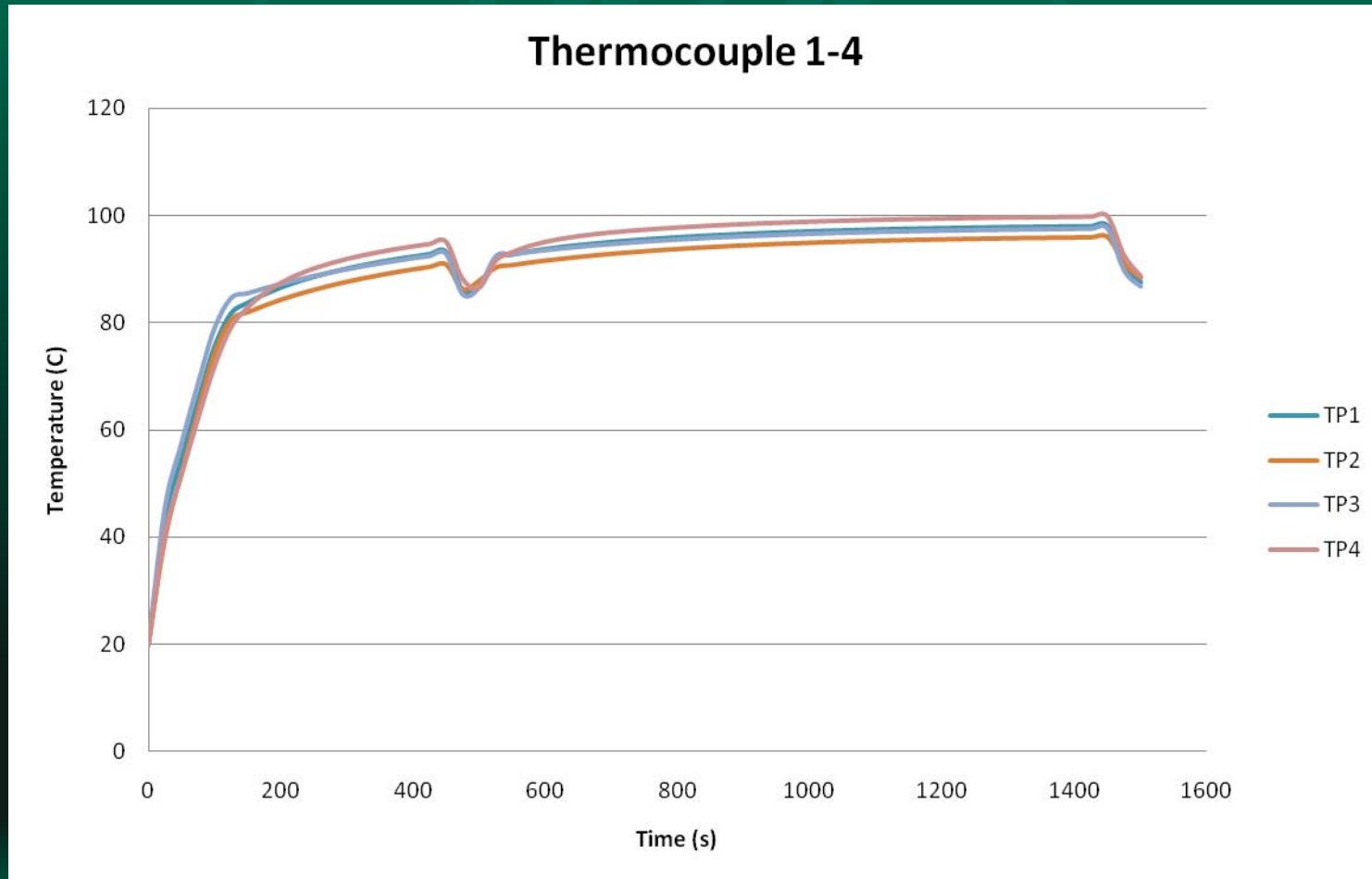
probe\_card\_assem\_thermal\_sim\_RA : LC3b-heater-convecting-1ip Result  
Load Case 1, Increment 18, Time : 4.250e+002 s  
Temperature - Nodal, Scalar  
Min : 8.723e+001, Max : 9.497e+001, C



# Environment Results



# Probe Card Thermal Profile



# Environment Conclusions

- Probe Card stabilizes at 94 deg C, both modes
- PCECU reaches stability with 50% improvement
- No significant delta seen with a 60 sec reload

# Conclusion

- PCECU thermal value is set once card has been profiled for thermal stability
- PCECU reduces the amount of variation, downtime, and customization in a Thermal Probe Cost Model (TPCM) = Reduced Cost (\$\$\$)
- PCECU is common solution across the prober, thus minimizing custom solutions to the probe card = Reduced Cost (\$\$\$)

# Understand the Environmental Conditions and you can .....



# Thank you

Mr. Martin Martinez  
Engineering Science Analysis Corp.  
6105 S. Ash, Suite A3  
Tempe, AZ 85283  
480-460-3727



<http://www.ESACORP.com>

Mr. Lou Molinari  
Probe Solutions  
743 Goldenrod St.  
Phoenix, AZ 85048  
480-460-3727



<http://www.ProbeSolutions.com>